

Notice of References Cited	Application/Control No. 10/522,496		Applicant(s)/Patent Under Reexamination INNEMAN ET AL.	
	Examiner Allen C. Ho		Art Unit 2882	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,881,965 B2	04-2005	Bowen et al.	250/492.2
*	B	US-6,624,431 B1	09-2003	Foster et al.	250/505.1
*	C	US-6,587,538 B2	07-2003	Igarashi et al.	378/19
*	D	US-6,470,072 B1	10-2002	Johnson, Mark A.	378/154
*	E	US-6,438,210 B1	08-2002	Castleberry, Donald Earl	378/154
*	F	US-6,175,615 B1	01-2001	Guru et al.	378/149
*	G	US-6,055,296	04-2000	Ferlic et al.	378/154
*	H	US-5,799,057	08-1998	Hoffman et al.	378/147
*	I	US-5,727,044	03-1998	Fraser et al.	378/149
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*	K	US-5,459,771	10-1995	Richardson et al.	378/119
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.